



P-CHANNEL ENHANCEMENT MODE MOSFET

Product Summary

BV _{DSS}	R _{DS(ON)} Max	I _D T _A = +25°C
201/	78mΩ @ V _{GS} = -8V	-3.4A
-20V	100mΩ @ V _{GS} = -4.5V	-3.0A

Description

This new generation MOSFET is designed to minimize the footprint in handheld and mobile application. It can be used to replace many small signals MOSFET with as really small footprint.

Applications

- Battery Management
- Load Switch
- Battery Protection
- · Handheld and Mobile Application

ESD PROTECTED TO 4 KV



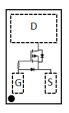
- Low Qg & Qgd
- Small Footprint
- Low Profile 0.20mm Height
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

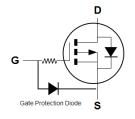
Mechanical Data

- Case: X4-DSN1006-3
- Terminal Connections: See Diagram Below
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish NiPdAu or NiAu Solderable per MIL-STD-202, Method 208 (4)
- Weight: 0.00029 grams (Approximate)









Equivalent Circuit

Ordering Information (Note 4)

Part Number	Case	Packaging
DMP2078LCA3-7	X4-DSN1006-3	10k/Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/

Marking Information



O = Product Type Marking Code YW = Date Code Marking Y or \overline{Y} = Year (ex: 0 = 2020) W or \overline{W} = Week (ex: a =week 27; z represents week 52 and 53)

Date Code Key

Year	2017		2020	2021	2022	2023	2024	2025	2026	2027	2028	2029
Code	7		0	1	2	3	4	5	6	7	8	9
Week	1-26			27-52				53				
Code		Δ	∖-Z			а	ı-Z				Z	

February 2020

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Maximum Ratings (@TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit		
Drain-Source Voltage	V _{DSS}	-20	V		
Gate-Source Voltage	Vgss	-12	V		
Continuous Drain Current (Note 5) V _{GS} = -8V	Steady State	T _A = +25°C T _A = +70°C	lo	-3.4 -2.7	А
Continuous Drain Current (Note 5) V _{GS} = -4.5V	I _D	-3.0 -2.4	А		
Pulsed Drain Current (Note 6)	I _{DM}	-13	Α		
Human Body Model (HBM)	$V_{(ESD)}$	4	kV		

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 7)	PD	0.81	W
Thermal Resistance, Junction to Ambient @T _A = +25°C (Note 7)	R _{0JA}	155.4	°C/W
Power Dissipation (Note 5)	PD	1.4	W
Thermal Resistance, Junction to Ambient @T _A = +25°C (Note 5)	R _{θJA}	90.4	°C/W
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

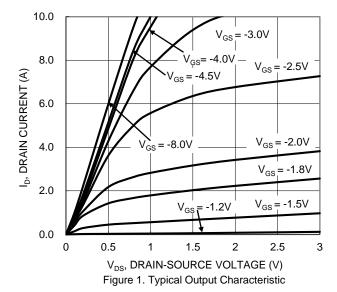
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)			•		•	•	
Drain-Source Breakdown Voltage	BVDSS	-20	_	_	V	V _G S = 0V, I _D = -250μA	
Zero Gate Voltage Drain Current T _J = +25°C	IDSS	_	_	-100	nA	V _{DS} = -16V, V _{GS} = 0V	
Gate-Source Leakage	Igss	_	_	-50	nA	Vgs = -12V, Vps = 0V	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V _{GS(TH)}	-0.7	-0.9	-1.2	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$	
		_	64	78		$V_{GS} = -8V, I_{D} = -0.5A$	
Static Drain-Source On-Resistance	Process	_	77	100	mΩ	$V_{GS} = -4.5V$, $I_{D} = -0.5A$	
Static Dialit-Source Off-Nesistance	RDS(ON)	_	113	165	11152	$V_{GS} = -2.5V, I_D = -0.5A$	
		_	188	600		$V_{GS} = -1.8V, I_D = -0.1A$	
Diode Forward Voltage	VsD	_	-0.7	-1.0	V	V _G S = 0V, I _S = -0.5A	
Reverse Recovery Charge	Qrr	_	1.3	_	nC	V _{DD} = -10V, I _F = -1A,	
Reverse Recovery Time	t _{RR}	_	7.7	_	ns	di/dt = 100A/µs	
DYNAMIC CHARACTERISTICS (Note 9)	•	•	•		•	•	
Input Capacitance	Ciss	_	152	228		10)/)/	
Output Capacitance	Coss	_	78	117	pF	$V_{DS} = -10V, V_{GS} = 0V,$ f = 1MHz	
Reverse Transfer Capacitance	Crss	_	4.3	6.4			
Series Gate Resistance	R _G	_	21	31	Ω	$f = 1MHz$, $V_{GS} = 0V$, $V_{DS} = 0V$	
Total Gate Charge	Qg	_	1.1	1.6			
Gate-Source Charge	Qgs	_	0.2	_	nC	$V_{GS} = -4.5V$, $V_{DS} = -10V$,	
Gate-Drain Charge	Q _{gd}	_	0.2	_	i iiC	$I_D = -0.5A$	
Gate Charge at VTH	Q _{g(th)}	_	3.6	_			
Turn-On Delay Time	tD(ON)	_	4.1	6.1			
Turn-On Rise Time		_	5.6	_		$V_{DS} = -10V, V_{GS} = -4.5V,$	
Turn-Off Delay Time	t _{D(OFF)}	_	9.5	14.2	ns	$R_G = 2\Omega$, $I_D = -0.5A$	
Turn-Off Fall Time	tF	_	4.6	_	1		

Notes:

- 5. Device mounted on FR-4 material with 1inch² (6.45cm²), 2oz. (0.071mm thick) Cu.
- 6. Repetitive rating, pulse width limited by junction temperature.
- 7. Device mounted on FR-4 PCB with minimum recommended pad layout, single sided.
- 8. Short duration pulse test used to minimize self-heating effect.
- 9. Guaranteed by design. Not subject to production testing.





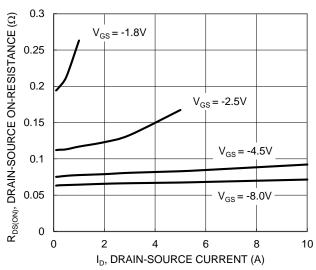


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

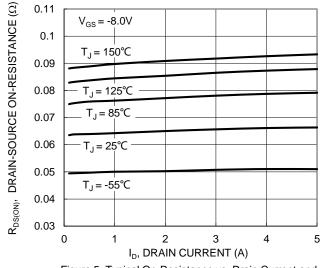


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

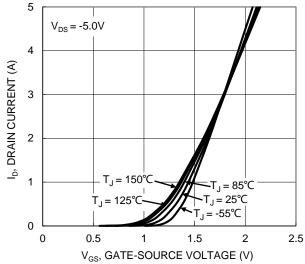


Figure 2. Typical Transfer Characteristic

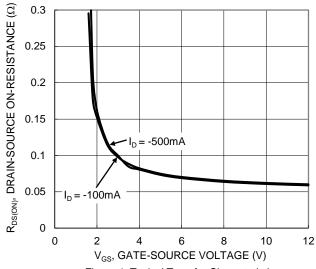


Figure 4. Typical Transfer Characteristic

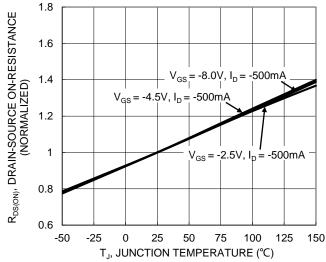


Figure 6. On-Resistance Variation with Junction Temperature



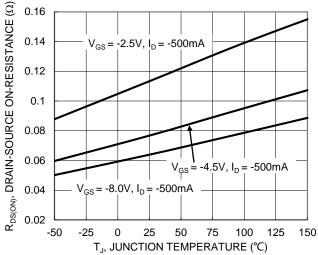
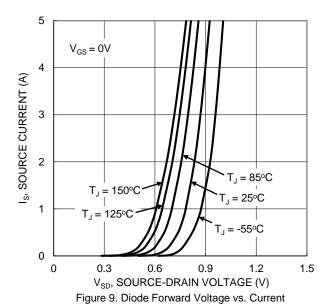


Figure 7. On-Resistance Variation with Junction Temperature



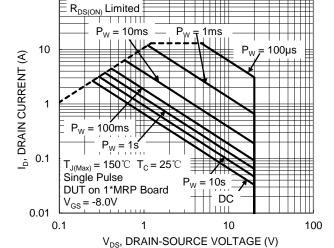


Figure 11. SOA, Safe Operation Area

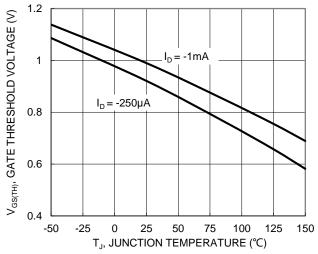
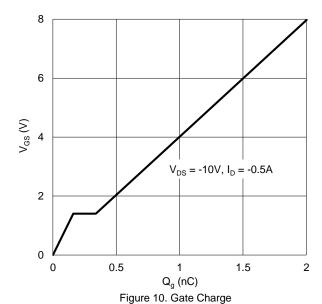


Figure 8. Gate Threshold Variation vs. Junction Temperature



100



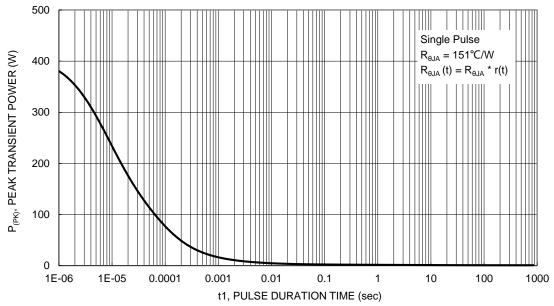


Figure 12. Single Pulse Maximum Power Dissipation

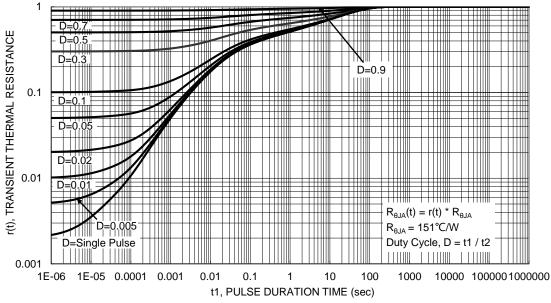
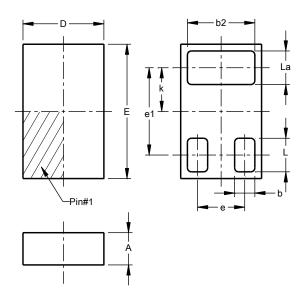


Figure 13. Transient Thermal Resistance



Package Outline Dimensions

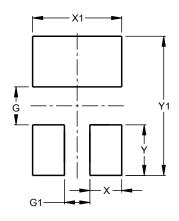
X4-DSN1006-3



X4-DSN1006-3						
Dim	Min	Max	Тур			
Α	0.18	0.22	0.20			
b	0.14	0.16	0.15			
b2	0.49	0.51	0.50			
D	0.56	0.64	0.60			
Е	0.96	1.04	1.00			
е			0.35			
e1			0.65			
k			0.325			
L	0.24	0.26	0.25			
La	0.24	0.26	0.25			
All Dimensions in mm						

Suggested Pad Layout

X4-DSN1006-3



Dimensions	Value (in mm)
G	0.40
G1	0.20
Х	0.15
X1	0.50
Y	0.25
Y1	0.90



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